

Notice of References Cited	Application/Control No. 09/785,424		Applicant(s)/Patent Under Reexamination PARK ET AL.	
	Examiner David Y. Chung		Art Unit 2871	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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*	C	US-6,124,911	09-2000	Nakamura et al.	349/113
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NON-PATENT DOCUMENTS

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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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